

Notice of References Cited

Application/Control No.

09/774,989

Applicant(s)/Patent Under

Reexamination

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,577,992	06-2003	Tcherniaev et al.	703/14
	B	US-5,910,897	06-1999	Dangelo et al.	364/488
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Bogliolo et al., "Reliability evaluation of combinational logic circuits by symbolic simulation", IEEE 1995
	V	Cabodi et al., "Improved Reliability analysis of large finite state machines", IEEE 1996
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.